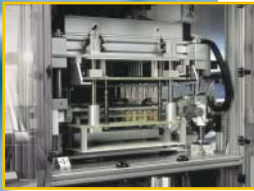


Inline Scorpion

Turn Key, High Speed, Inline In-Circuit Test Solution for High Volume Production

- ▶ In-Circuit test system (MDA)
- ▶ Up to 1,024 test pins
- ▶ Single or double sided testing – single fixture
- ▶ Complete fixture change in less than one minute
- ▶ Cycle time 4 seconds plus test time
- ▶ Maximum board size 350 mm x 400 mm
- ▶ Extended fault detection
- ▶ Built-in network analyzer
- ▶ SMEMA compliant conveyor
- ▶ Automatic program generation and debugging
- ▶ Optional functional testing
- ▶ Full software compatibility to Flying Scorpion
- ▶ Small Footprint: 1050 mm L x 1050 mm W x 1660 mm H





Technical Description

▶ The Inline Scorpion is a fully automated in-circuit (MDA) test system for high volume production with the added advantage of a very fast change over time for different assemblies – less than one minute, including fixture change.

▶ The Inline Scorpion is ideally suited for the modern flexible manufacturing line requiring a fast product change over. Upper and lower fixtures are a single unified fixture with coding for proper conveyor width and automatic call up of the test program.

Technical Notes

Test Handling System:

• System footprint	1050 mm L x 1050 mm W x 1660 mm H
• Weight	500 kg
• Transport height	900 mm ± 70 mm
• Conveyor width	50 mm to 430 mm
• Controller	Siemens S7 PLC with control panel
• Height of components	60 mm max. top; 15 mm max. bottom
• Board conveyor clearance	3 mm
• Maximum board size	350 mm x 400 mm
• Fixturing	Multi level; single or optional double sided
• Electrical requirements	400 VAC (3 phase), 16 A
• Compressed air	5 to 6 bar

Test Handling Options:

- Independent signal interface for upper fixture for double sided testing
- Automatic conveyor adjustment
- Increased space for bottom side components
- Extended SMEMA protocol support
- Remote diagnostics

Test System Specifications:

• Test pins	64 to 1,024 in increments of 64
• Stimulus	Two 4 quadrant DC Stimuli from 10 mV to 10 V and 2.44 nA to 1 A; One 25 mV to 100 V @ 20 mA
• Relay matrix	4-wire measurements using any test point combination
• Guarding	Guarding at each test point. Up to 1 A with programmable current limit
• Voltage	100 V
• Current	1 A max. continuous; 0.5 A switched
• Measurement	12-bit DC voltmeter. Range from 80 mV to 100 V, resolution 19 µV; measurement programmable from 2 µsec to 16 sec. in 2 µsec increments
• Resistance	1 mΩ to 360 MΩ
• Capacitance	10 pF to 10 F
• Inductance	10 µH to 10 H
• Voltage	19 µV to 100 V

Test System Options:

• CScan	Detects faults including: open leads on ICs including BGAs; reverse electrolytic capacitors; connector pins and decoupling capacitors
• ChipScan	Detects open leads on ICs including BGAs with heat sinks
• BodeScan	Built-in network analyzer for detecting missing or wrong small value components in complex RF networks
• Functional test	IEEE, VXI, LabView, MetLab, etc.

Data subject to alteration without notice!
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